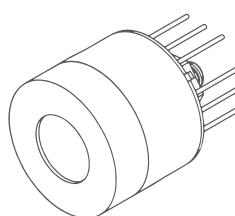
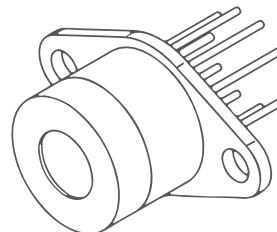


PCI-12 SERIES

HgCdTe thermoelectrically cooled optically immersed photoconductive infrared detectors



3TE-T08



3TE-T066

FEATURES

- Spectral range: over 14.0 μm
- Back-side illuminated
- Unique immersion lens technology applied
- No minimum order quantity required
- Detector **PCI-3TE-12-1x1-T08-wZnSeAR-36** is a **Selected Line product**

APPLICATIONS

- FTIR spectroscopy
- Gas detection, monitoring and analysis: C_2H_6 , NH_3
- Laser measurements: power monitoring and control, beam profiling and positioning, calibration

RELATED PRODUCT

- **SM-I-12** detection module (p. 122)

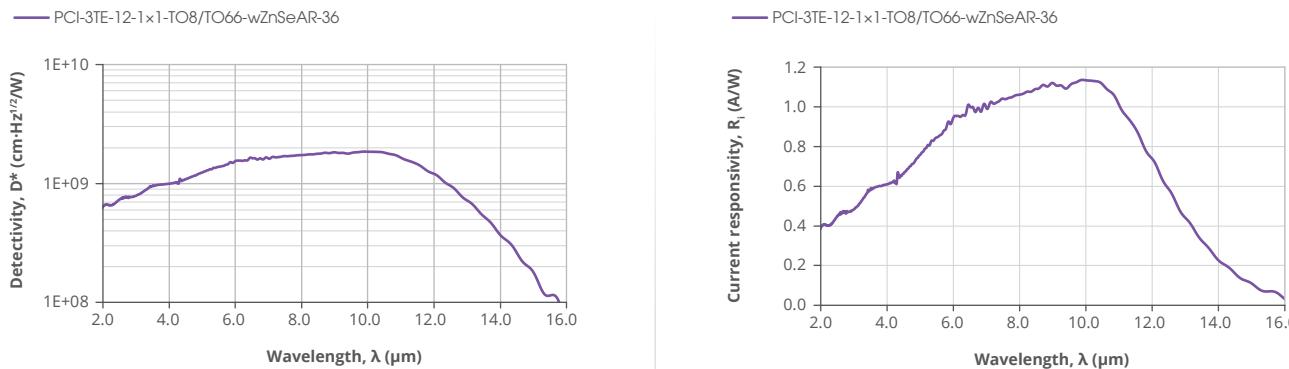
SERIES DESCRIPTION

Detector symbol	Cooling (p. 191)	Temperature sensor (p. 192)	Optical area, A_{or} mm \times mm	Optical immersion (p. 188)	Package	Acceptance angle, Φ , deg.	Window (p. 193)
PCI-3TE-12-1x1-T08-wZnSeAR-36	3TE $T_{\text{chip}} \leq 210\text{K}$	thermistor	1x1	hyperhemisphere	TO8	~36	wZnSeAR (3 deg. zinc selenide, anti-reflection coating)
PCI-3TE-12-1x1-T066-wZnSeAR-36					TO66		

SPECIFICATION ($T_{\text{amb}} = 293\text{ K}$, $V_b = 0.9\text{ V}$)

Detector symbol	Peak wavelength	Specific wavelength	Cut-off wavelength (10%)	Detectivity			Current responsivity		Time constant	Dynamic resistance	Bias voltage	1/f corner frequency
	λ_{peak}	λ_{spec}	$\lambda_{\text{cut-off}}$	$D^*(\lambda_{\text{peak}}, 20\text{kHz})$	$D^*(\lambda_{\text{spec}}, 20\text{kHz})$	$R_i(\lambda_{\text{peak}})$	$R_i(\lambda_{\text{spec}})$	τ	R	V_b	f_c	
	μm	μm	μm	cm·Hz $^{1/2}$ /W	cm·Hz $^{1/2}$ /W	A/W	A/W	ns	Ω	V	kHz	
PCI-3TE-12-1x1-T08-wZnSeAR-36	Typ.	Typ.	Typ.	Typ.	Min.	Typ.	Typ.	Min.	Typ.	Typ.	Max.	Typ.
PCI-3TE-12-1x1-T08-wZnSeAR-36	10.0±0.5	12.0	14.0	1.6×10^9	9.0×10^8	1.2×10^9	1.0	0.07	0.7	5	200	0.9
PCI-3TE-12-1x1-T066-wZnSeAR-36												20

SPECTRAL RESPONSE (Typ., $T_{\text{amb}} = 293 \text{ K}$)



MECHANICAL LAYOUT AND PINOUT

- 3TE-TO8 package
 - Technical drawing (p. 207)
- 3TE-TO66 package
 - Technical drawing (p. 208)

RECOMMENDED AMPLIFIERS

Detector symbol	Amplifier type
PCI-3TE-12-1x1-T08-wZnSeAR-36	AIP series (p. 126) PIP series (p. 129) MIP series (p. 132) SIP-T08 series (p. 135)

ABSOLUTE MAXIMUM RATINGS

Parameter	Test conditions/remarks	Value	Unit
Ambient operating temperature, T_{amb}	Operation at $T_{\text{amb}} > 30^\circ\text{C}$ may increase the active element temperature and reduce the performance of the detector below specified parameters	-20 to 30	°C
Storage temperature, T_{stg}		-20 to 50	°C
Soldering temperature	Within 5 s or less	≤ 300	°C
Storage humidity	No dew condensation	10 to 90	%
Maximum incident optical power density	Continuous wave (CW) or single pulses $> 1 \mu\text{s}$ duration	2.5	W/cm^2
	Single pulses $< 1 \mu\text{s}$ duration	10	kW/cm^2
Maximum bias voltage, $V_{\text{b max}}$		1.5	V
Maximum TEC voltage, $V_{\text{TEC max}}$	3TE	3.6	V
Maximum TEC current, $I_{\text{TEC max}}$	3TE	0.45	A

Stresses beyond those listed under absolute maximum ratings may cause permanent damage to the device. Constant or repeated exposure to absolute maximum rating conditions may affect the quality and reliability of the device.